

<b>Notice of References Cited</b>	Application/Control No. 10/613,495	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,780,924	08-2004	Shih et al.	524/555
	B	US-2001/0004487	06-2001	Kaneko et al.	428/195
	C	US-2003/0186003	10-2003	Nakano et al.	428/32.1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

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	X	

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